

Silicon Diodes and Their Applications*

Chang Zhou¹, Siyu Wang², Haoran Du³

Abstract—The purpose of this laboratory experiment was to explore the current-voltage properties of diodes. The main concepts we investigated in this lab are the rectification, zener diodes, AC to DC conversion, and forward and reverse bias.

I. INTRODUCTION

Silicon diodes are two-terminal devices that are composed of the p-n junction. They are used for rectification. Standard diodes allow current in only one direction and do not conduct in reverse bias. However, zener diodes can operate in reverse-breakdown. This lab explores the properties of different diodes. We use an operational amplifier to keep track both the voltage across and the current through the diode under test.

In this report, we will present the result we obtained during the experiment and analysis them using knowledge we learned from class.

II. EXPERIMENTS PROCEDURES AND RESULT

A. Part 1: I-V Characteristics Using a Curve Tracer

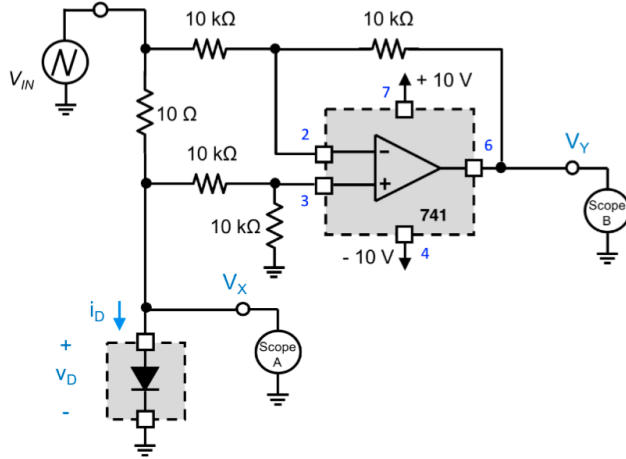


Fig. 1. Circuit for i-v diode measurement in Part 1

In the first part of the lab, before we construct the above circuit shown in Fig. ?? using the 1N4148 signal diode. We

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¹C. Zhou is with the Department of Electrical and Computer Engineering, Faculty of Engineering, McGill University, Montreal, QC H3A 0E9 Canada. (chang.zhou2@mail.mcgill.ca)

²S. Wang is with the Department of Electrical and Computer Engineering, Faculty of Engineering, McGill University, Montreal, QC H3A 0E9 Canada. (siyu.wang5@mail.mcgill.ca)

³H. Du is with the Department of Electrical and Computer Engineering, Faculty of Engineering, McGill University, Montreal, QC H3A 0E9 Canada. (haoran.du@mail.mcgill.ca)

first verify that the voltage shown in scope B is 10 times greater than the current i_D by replacing the diode with a 100 ohm resistor. The input signal is a triangle wave with 4 volt peak to peak voltage and zero offset. The experiment result is shown in Fig. ??; the black one is V_a and the grey one is V_b . V_b has an amplitude of 1.2645V (2.529 V peak-to-peak) and V_a has an amplitude of 129.305 mV (258.61 mV peak-to-peak); by ohm's law the amplitude of the current through the resistor is 12.645 mA, which is about 10 times less than V_b . Thus, the circuit works properly.

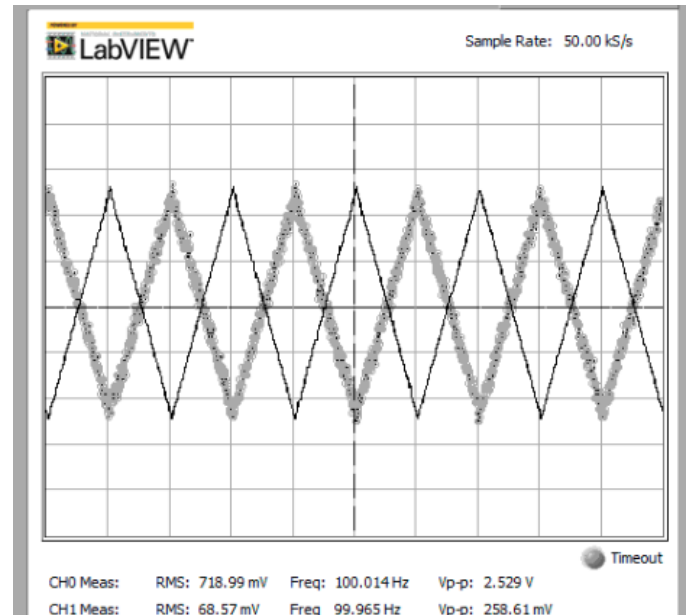


Fig. 2. Result for testing the op-amp; black is V_a and grey is V_b

Next, we replace the resistor with the 1N4148 signal diode, while keep the input signal the same as before. Fig. ?? shows the simulation and the experiment result.

This simulation diagram by itself is not very valuable and nothing can really be generated of from this form; therefore, we plot the i-v diagram of this diode, and the result is shown below in Fig. ?? . By observing the graph, we find that the cut-in voltage is 0.5 V. Also, by using the formula slope = $\Delta I / \Delta V$, and the two pairs of data points (circled in red) from the i-v diagram in Fig. ??, we calculate the slope at 0.7 V is 123.55 mA/V.

The maximum voltage difference between the actual i-v curve and that predicted by the piecewise linear model over a voltage range from -2 to +2 V is very small (0.1V). The piecewise linear approximation is a reliable model.

Then, we replace the 1N4148 signal diode with an 1N4005

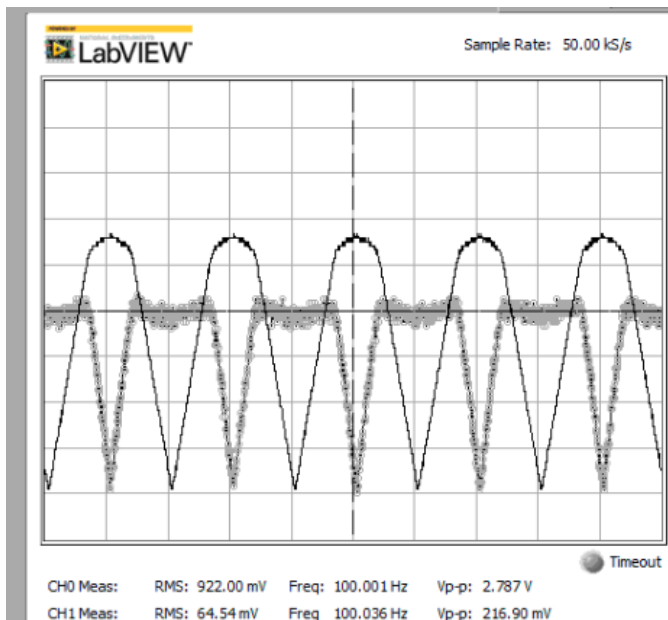


Fig. 3. Simulation result of the 1N4148 diode; black is Va and grey is Vb

diode, Fig. ?? shows the simulation and the experiment results. The results are similar.

Finally, we reverse the 1N4148 diode, we observe that the behavior is also reversed because the triangle wave is symmetric with respect to 0 V. Fig. ?? shows the i-v curve of the reversed 1N4148 diode.

B. Part 2: Diode Temperature Effect

In part 2, we observe the behaviour of a diode under different temperature conditions. The diode 1N4148 was tested first in room temperature, then in a lower temperature and a higher temperature by the above circuit in Fig. ?. We keep track of the temperature by the hand-held thermal imager.

By observing the results from in Fig. ?, we find that the increase in the temperature will lower the cut in voltage of the diode. This is expected because as the overall energy in the electrons of semi-conductors increases, the amount of extra energy need to be provided to make the diode conduct decreases.

III. CONCLUSIONS

start here.

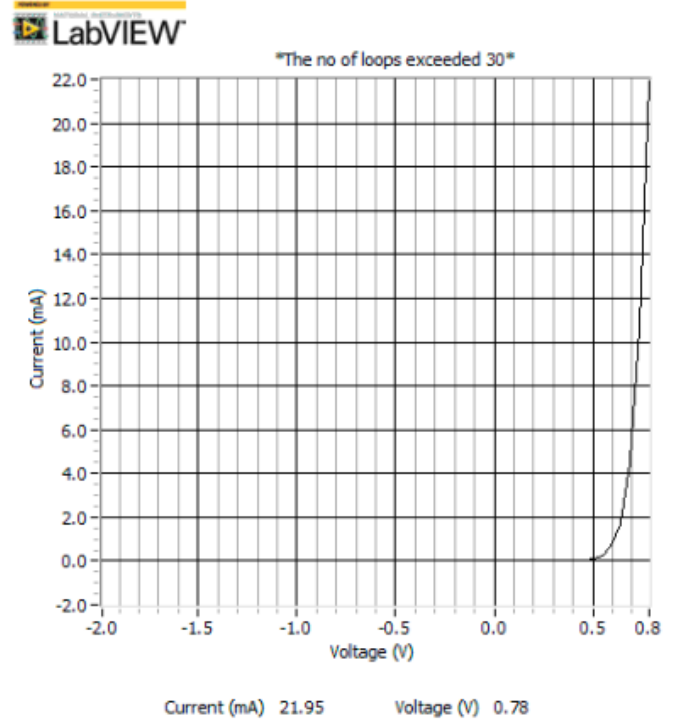


Fig. 4. The i-v curve of the 1N4148 diode

| | |
|-------|--------|
| 0.007 | -0.005 |
| 0.061 | -0.005 |
| 0.108 | -0.003 |
| 0.160 | -0.005 |
| 0.207 | -0.005 |
| 0.261 | -0.003 |
| 0.308 | -0.003 |
| 0.361 | 0.000 |
| 0.408 | 0.009 |
| 0.460 | 0.035 |
| 0.504 | 0.095 |
| 0.550 | 0.263 |
| 0.595 | 0.681 |
| 0.638 | 1.689 |
| 0.688 | 4.531 |
| 0.737 | 10.585 |
| 0.785 | 21.949 |

Fig. 5. The data points from i-v curve of the 1N4148 diode; the first column represents the voltage in V; the second column represents the current in mA

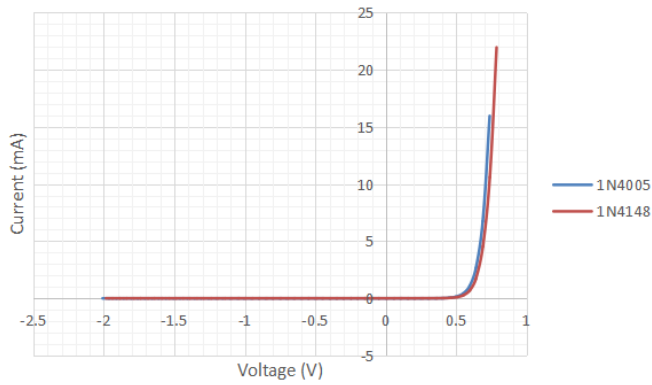


Fig. 6. Comparison of the i-v curves for 1N4005 diode and 1N4148 diode

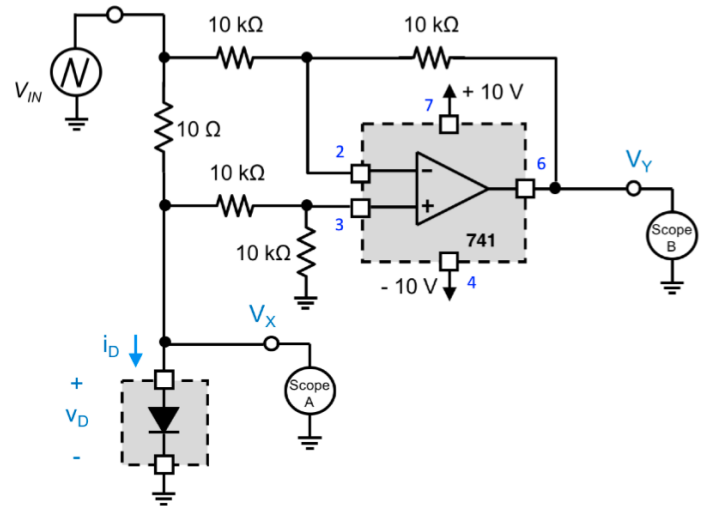


Fig. 8. Circuit for i-v diode measurement in Part 1

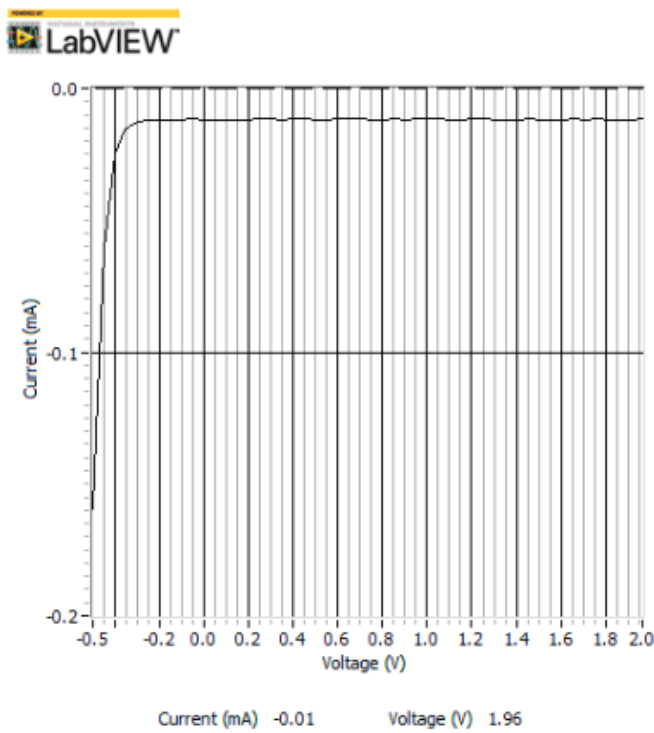


Fig. 7. The i-v curve of the reversed 1N4148 diode

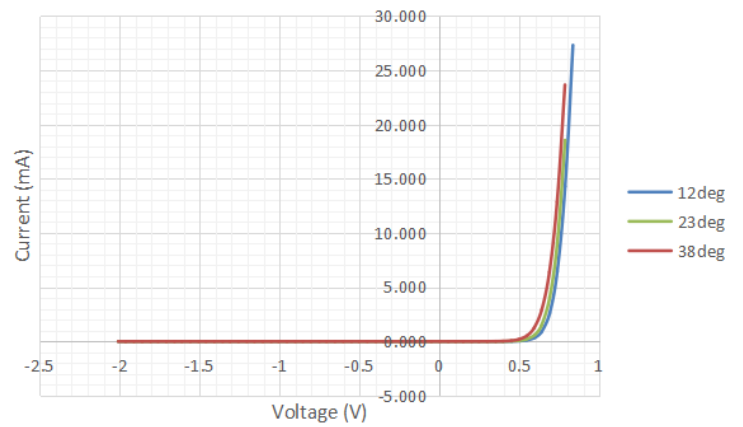


Fig. 9. The i-v measurement for 1N4148 diode at different temperatures